

# PolarHV<sup>™</sup> HiPerFET **Power MOSFET** ISOPLUS247™

## **IXFR 180N15P**

# **I**<sub>D25</sub> $\boldsymbol{R}_{\text{DS(on)}}$

150 100

13  $m\Omega$ 200

ns

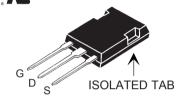
## (Electrically Isolated Back Surface)

N-Channel Enhancement Mode Avalanche Rated Fast Intrinsic Diode

Symbol	Test Conditions	Maximum R	Maximum Ratings			
V <sub>DSS</sub>	T <sub>J</sub> = 25° C to 175° C	150	V			
$\mathbf{V}_{\mathtt{DGR}}$	$T_{_J}$ = 25° C to 175° C; $R_{_{GS}}$ = 1 M $\Omega$	150	V			
$\mathbf{V}_{gss}$	Continuous	±20	V			
$\mathbf{V}_{\mathtt{GSM}}$	Transient	±30	V			
I <sub>D25</sub>	T <sub>C</sub> = 25° C	100	Α			
I <sub>D(RMS)</sub>	External Lead current limit	75	Α			
I <sub>DM</sub>	$T_{\rm C} = 25^{\circ}$ C, pulse width limited by $T_{\rm JM}$	380	Α			
I <sub>AR</sub>	T <sub>c</sub> =25°C	60	Α			
E <sub>AR</sub>	T <sub>c</sub> = 25° C	100	mJ			
<b>E</b> <sub>AS</sub>	T <sub>C</sub> =25° C	4	J			
dv/dt	$I_{\rm S} \leq I_{\rm DM}$ , di/dt $\leq 100$ A/ $\mu$ s, $V_{\rm DD} \leq V_{\rm DSS}$ , $T_{\rm J} \leq 150^{\circ}$ C, $R_{\rm G}$ = 4 $\Omega$	10	V/ns			
$\overline{\mathbf{P}_{D}}$	T <sub>C</sub> = 25° C	300	W			
T <sub>J</sub>		-55 +175	°C			
T <sub>JM</sub> T <sub>stg</sub>		175 -55 +150	°C			
T <sub>L</sub>	1.6 mm (0.062 in.) from case for 10 s	300	°C			
V <sub>ISOL</sub>	50/60 Hz, RMS, 1 minute	2500	V~			
F <sub>d</sub>	Mounting force	20120 / 4.526	N/lb			
Weight		5	g			

<b>Symbol</b> (T <sub>J</sub> = 25° C, u	Test Conditions unless otherwise specified)		Ch Min.	_	ristic Val	
V <sub>DSS</sub>	$V_{GS} = 0 \text{ V}, I_{D} = 250 \mu\text{A}$		150			V
$V_{GS(th)}$	$V_{DS} = V_{GS}$ , $I_{D} = 4 \text{ mA}$		2.5		5.0	V
GSS	$V_{GS} = \pm 20 V_{DC}, V_{DS} = 0$				±100	nA
I <sub>DSS</sub>	$V_{DS} = V_{DSS}, V_{GS} = 0 V$	T <sub>J</sub> = 150° C			25 1.5	μA mA
R <sub>DS(on)</sub>	$V_{GS} = 10 \text{ V}, I_{D} = I_{T}, \text{ Note } 1$				13	mΩ





G = Gate D = Drain S = Source

## **Features**

- <sup>1</sup> International standard isolated package
- <sup>1</sup> UL recognized package
- Silicon chip on Direct-Copper-Bond substrate
  - High power dissipation
  - Isolated mounting surface
- 2500V electrical isolation
- Unclamped Inductive Switching (UIS)
- Low package inductance
  - easy to drive and to protect
- Fast intrinsic diode

### **Advantages**

- <sup>1</sup> Easy to mount
- Space savings
- High power density

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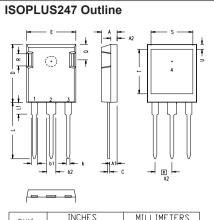


Symbol	Test Conditions Character ( $T_J$ = 25° C, unless Min.	otherwi	ristic Values se specified) Max.
g <sub>fs</sub>	$V_{DS} = 10 \text{ V}; I_{D} = I_{T}, \text{ Notes } 1, 2$ 55	86	S
C <sub>iss</sub> C <sub>oss</sub> C <sub>rss</sub>	$ V_{GS} = 0 \text{ V}, V_{DS} = 25 \text{ V}, f = 1 \text{ MHz} $	7000 2250 515	pF pF pF
$\mathbf{t}_{d(on)}$ $\mathbf{t}_{r}$ $\mathbf{t}_{d(off)}$ $\mathbf{t}_{f}$	$V_{GS} = 10 \text{ V}, V_{DS} = 0.5 V_{DSS}, I_{D} = 60A$ $R_{G} = 3.3 \Omega \text{ (External)}$	30 32 150 36	ns ns ns
$egin{aligned} oldsymbol{Q}_{g(on)} \ oldsymbol{Q}_{gs} \ oldsymbol{Q}_{gd} \end{aligned}$	$ V_{GS} = 10 \text{ V}, V_{DS} = 0.5 V_{DSS}, I_{D} = I_{T} $	240 55 140	nC nC nC
R <sub>thJC</sub>		0.15	0.5 ° C/W

#### Source-Drain Diode

**Characteristic Values**  $(T_J = 25^{\circ} C, unless otherwise specified)$ 

Symb	ol Test	Conditions n	nin.	typ.	max.	
I <sub>s</sub>	V <sub>GS</sub> =	0 V			180	Α
I <sub>SM</sub>	Repe	titive			380	Α
V <sub>SD</sub>	$I_F = I_S$	, V <sub>GS</sub> = 0 V, Note 1			1.5	V
t <sub>rr</sub>	) I <sub>F</sub> = 2	5A, -di/dt = 100 A/μs			200	ns
$\mathbf{Q}_{_{\mathrm{RM}}}$	\ \ \ \ \ \ \ \ \ \ \ \ \ R =	100V, V <sub>GS</sub> = 0V		0.6		μС
I <sub>RM</sub>	J			6		Α



SYM	INCE	1E.S	MILLIMETERS			
3114	MIN	MAX	MIN	MAX		
Α	.190	.205	4.83	5.21		
A1	.090	.100	2.29	2.54		
A2	.075	.085	1.91	2.16		
Ь	.045	.055	1.14	1.40		
ь1	.075	.084	1.91	2.13		
b2	.115	.123	2.92	3.12		
С	.024	.031	0.61	0.80		
D E	.819	.840	20.80	21.34		
E	.620	.635	15.75	16.13		
е	.215	BSC	5.45	BSC		
L	.780	.800	19.81	20.32		
L1	.150	.170	3.81	4.32		
Q	.220	.244	5.59	6.20		
R	.170	.190	4.32	4.83		
S	.520	.540	13.21	13.72		
T	.620	.640	15.75	16.26		
U	.065	.080	1.65	2.03		

1 - GATE 2 - DRAIN (COLLECTOR) 3 - SOURCE (EMITTER) 4 - NO CONNECTION

NOTE: This drawing will meet all dimensions requirement of JEDEC outline TO-247AD except screw hole.

## Notes:

- 1. Pulse test, t  $\leq$ 300  $\mu$ s, duty cycle d  $\leq$  2 %;
- 2. Test current  $I_{\scriptscriptstyle T}$  = 90 A.



Fig. 1. Output Characteristics @ 25°C

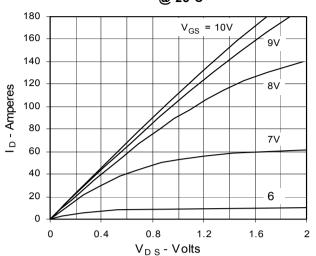


Fig. 3. Output Characteristics @ 150°C

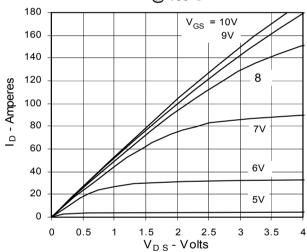


Fig. 5.  $R_{DS(on)}$  Normalized to  $I_D$  = 90A Value vs. Drain Current

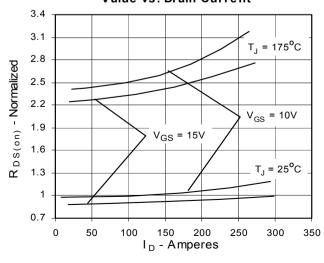


Fig. 2. Extended Output Characteristics @ 25°C

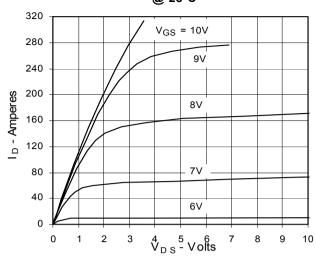


Fig. 4.  $R_{DS(on)}$  Normalized to  $I_D = 90A$ Value vs. Junction Temperature

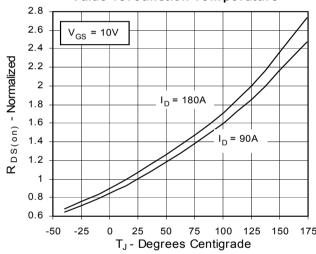


Fig. 6. Drain Current vs. Case Temperature

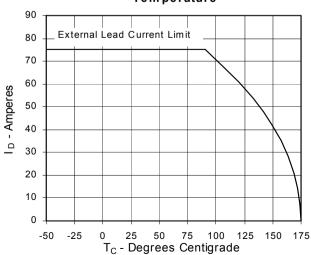


Fig. 7. Input Admittance

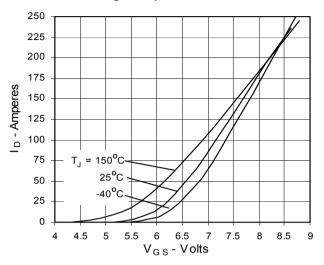


Fig. 9. Source Current vs. Source-To-Drain Voltage

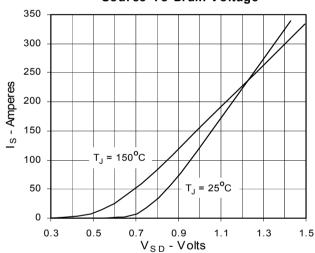


Fig. 11. Capacitance

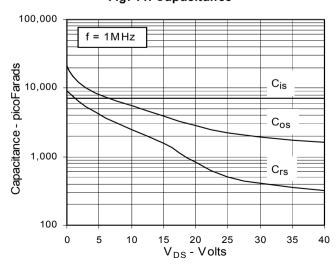


Fig. 8. Transconductance

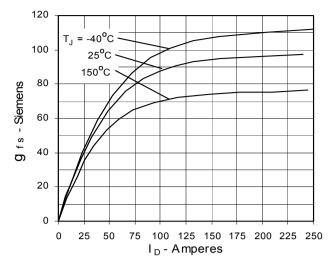


Fig. 10. Gate Charge

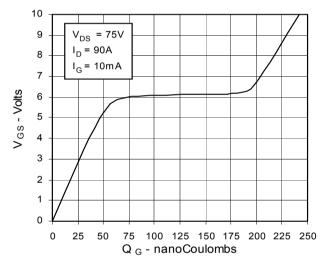
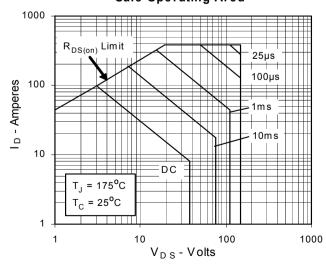


Fig. 12. Forward-Bias Safe Operating Area



IXYS reserves the right to change limits, test conditions, and dimensions.



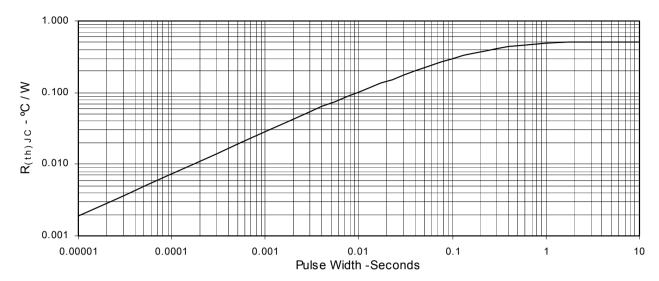


Fig. 13. Maximum Transient Thermal Resistance

